



PATENT

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

APPLICANTS: GEUM-JIN YUN, et al. CONF. NO.: 6863  
SERIAL NO.: 10/759,267 GROUP: 2829  
FILED: January 20, 2004 EXAMINER: Paresh H. Patel  
FOR: INTEGRATED MONITORING BURN-IN TEST METHOD FOR  
MULTI-CHIP PACKAGE  
DOCKET NO.: 2557-000206/US

*Free  
Only*

**RESPONSE TO RESTRICTION REQUIREMENT**

Customer Service Window  
Randolph Building  
401 Dulany Street  
Alexandria, VA 22314

April 1, 2005

Dear Sir:

Responsive to the Examiner's Restriction Requirement dated March 2, 2005, the following remarks are respectfully submitted in connection with the above-referenced application.

**Amendments to the Claims** begin on page 2 of this Amendment.

**Remarks** being on page 9 of this Amendment.

04/11/2005 JMCHILLA 00000006 080750 10759267

01 FC:1202 100.00 DA